

# DS92001 3.3V B/LVDS-BLVDS Buffer

### **General Description**

The DS92001 B/LVDS-BLVDS Buffer takes a BLVDS input signal and provides an BLVDS output signal. In many large systems, signals are distributed across backplanes, and one of the limiting factors for system speed is the "stub length" or the distance between the transmission line and the unterminated receivers on individual cards. Although it is generally recognized that this distance should be as short as possible to maximize system performance, real-world packaging concerns often make it difficult to make the stubs as short as the designer would like.

The DS92001 has edge transitions optimized for multidrop backplanes where the switching frequency is in the 200 MHz range or less. The output edge rate is critical in some systems where long stubs may be present, and utilizing a slow transition allows for longer stub lengths.

The DS92001, available in the LLP (Leadless Leadframe Package) package, will allow the receiver inputs to be placed very close to the main transmission line, thus improving system performance.

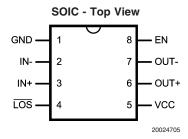
A wide input dynamic range allows the DS92001 to receive differential signals from LVPECL as well as LVDS sources. This will allow the device to also fill the role of an LVPECL-BLVDS translator.

The  $\overline{\text{LOS}}$  pin detects a non-driven B/LVDS bus state at the input and provides an active LOW output. The  $\overline{\text{LOS}}$  pin can be tied to the device's output enable pin (EN) to generate a TRI-STATE output state when the input is un-driven. The  $\overline{\text{LOS}}$  pin can also be used locally to inform the system of the bus state.

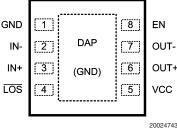
### **Features**

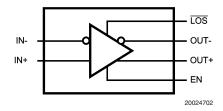
- Single +3.3 V Supply
- B/LVDS receiver inputs accept LVPECL signals
- TRI-STATE outputs
- Loss of Signal (LOS) pin detects a non-driven bus
- Receiver input threshold < ±100 mV
- Fast propagation delay of 1.4 ns (typ)
- Low jitter 400 Mbps fully differential data path
- Compatible with BLVDS 10-bit SerDes (40MHz)
- Compatible with ANSI/TIA/EIA-644-A LVDS standard
- Available in SOIC and space saving LLP package
- Industrial Temperature Range

## **Connection and Block Diagrams**









# **Functional Operation**

BLVDS Inputs	BLVDS Outputs		
[IN+] - [IN-]	OUT+	OUT-	
VID ≥ 0.1V	Н	L	
VID ≤ -0.1V	L	Н	
Full Fail-safe	Н	L	
OPEN/SHORTor Terminated			

# **Ordering Information**

Order Number	NS Pkg. No.	Pkg. Type
DS92001TMA	M08A	SOIC
DS92001TLD	LDA08A	LLP

## **Absolute Maximum Ratings** (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

-0.3V to +4VSupply Voltage (V<sub>CC</sub>) LVCMOS/LVTTL Input Voltage -0.3V to  $(V_{CC} + 0.3V)$ (EN) LVCMOS/LVTTL Output Voltage -0.3V to  $(V_{CC} + 0.3V)$ (LOS) B/LVDS Receiver Input Voltage (IN+, IN-) -0.3V to +4V**BLVDS** Driver Output Voltage -0.3V to +4V (OUT+, OUT-) **BLVDS Output Short Circuit** Continuous Current +150°C Junction Temperature Storage Temperature Range -65°C to +150°C Lead Temperature Range Soldering (4 sec.) +260°C

Maximum Package Power Dissipation at 25°C

M Package 726 mW

Derate M Package 5.8 mW/°C above +25°C

LDA Package 2.44 W

Derate LDA Package 19.49 mW/°C above +25°C

+25°C

**ESD Ratings** 

(HBM, 1.5kΩ, 100pF)  $\geq$ 2.5kV (EIAJ, 0Ω, 200pF)  $\geq$ 250V

# Recommended Operating Conditions

	Min	Тур	Max	Units
Supply Voltage (V <sub>CC</sub> )	3.0	3.3	3.6	V
Receiver Differential Input	0.1		2.4	IVI
Voltage (V <sub>ID</sub> ) with				
V <sub>CM</sub> =1.2V				
Operating Free Air	-40	+25	+85	°C
Temperature				
B/LVDS Input Rise/Fall		2	20	ns
20% to 80%				

### **Electrical Characteristics**

Over recommended operating supply and temperature ranges unless otherwise specified. (Notes 2, 3)

Symbol	Parameter	Min	Тур	Max	Units	
LVCMOS	/LVTTL DC SPECIFICATIONS (	EN)				
V <sub>IH</sub>	High Level Input Voltage		2.0		V <sub>CC</sub>	V
V <sub>IL</sub>	Low Level Input Voltage		GND		0.8	V
I <sub>IH</sub>	High Level Input Current	$V_{IN} = V_{CC}$ or 2.0V		+7	+20	μΑ
I <sub>IL</sub>	Low Level Input Current	V <sub>IN</sub> = GND or 0.8V	-10	±1	+10	μΑ
V <sub>CL</sub>	Input Clamp Voltage	$I_{CL} = -18 \text{ mA}$		-0.6	-1.5	V
LVCMOS	/LVTTL DC SPECIFICATIONS (	LOS)				
V <sub>OH</sub>	Output High Voltage	$I_{OH} = -4mA, V_{ID} \ge  200mV , V_{CM} = 1.2V$	V <sub>CC</sub> -0.4V	3.1	V <sub>CC</sub>	V
V <sub>OL</sub>	Output Low Voltage (Note 5)	$I_{OL} = 4mA, V_{ID} = 0V, V_{CM} = 1.2V$		0.15	0.4	V
I <sub>OSHLOS</sub>	Output Short Circuit Current (output high)(Note 4)	$V_{OUT} = 0V, 200mV \le V_{ID} \le 2V, V_{CM} = 1.5V$		-35	-60	mA
BLVDS C	OUTPUT DC SPECIFICATIONS	(OUT)				
IV <sub>OD</sub> I	Differential Output Voltage	$R_L = 27\Omega$	250	350	500	mV
	(Note 2)	$R_L = 50\Omega$	350	450	600	mV
$\Delta V_{OD}$	Change in Magnitude of V <sub>OD</sub> for Complimentary Output States	RL = $27\Omega$ or $50\Omega$ Figure 1, Figure 2			20	mV
Vos	Offset Voltage	$R_L = 27\Omega$ or $R_L = 50\Omega$	1.1	1.25	1.375	V
$\Delta V_{OS}$	Change in Magnitude of V <sub>OS</sub> for Complimentary Output States	Figure 1		2	20	mV
l <sub>oz</sub>	Output TRI-STATE Current	EN = 0V, V <sub>OUT</sub> = V <sub>CC</sub> or GND	-20	±5	+20	μΑ
I <sub>OFF</sub>	Power-Off Leakage Current	V <sub>CC</sub> = 0V or Open Circuit, V <sub>OUT</sub> = 3.6V	-20	±5	+20	μΑ

# **Electrical Characteristics** (Continued)

Over recommended operating supply and temperature ranges unless otherwise specified. (Notes 2, 3)

Symbol	Parameter	Conditions			Тур	Max	Units
BLVDS C	OUTPUT DC SPECIFICATIONS (	OUT)					
I <sub>OS1</sub>	Output Short Circuit Current (Note 4)	or	EN = $V_{CC}$ , $V_{CM}$ = 1.2V, $V_{ID}$ = 200mV, $V_{OUT+}$ = 0V, or $V_{ID}$ = -200mV, $V_{CM}$ = 1.2V, $V_{OUT-}$ = 0V		-30	-60	mA
			$V_{CM} = 1.2V$ , $V_{OUT+} = V_{CC}$ , or $V_{CM} = 1.2V$ , $V_{OUT-} = V_{CC}$		53	80	mA
I <sub>OSD</sub>	Differential Output Short Circuit Current (Note 4)	00 .5	= I200mVI, V <sub>CM</sub> . = 1.2V, V <sub>OD</sub> = 0V nd complement outputs through a		1301	1421	mA
B/LVDS I	RECEIVER DC SPECIFICATIONS	6 (IN)			•		
V <sub>TH</sub>	Differential Input High Threshold (Note 5)	$V_{CM} = +0.05V,$	+1.2V or +3.25V		-30	-5	mV
V <sub>TL</sub>	Differential Input Low Threshold (Note 5)			-70	-30		mV
V <sub>CMR</sub>	Common Mode Voltage Range (Note 5)			IV <sub>ID</sub> I/2		V <sub>CC</sub> - V <sub>ID</sub>  /2	V
I <sub>IN</sub>	Input Current	$V_{IN} = V_{CC}$ $V_{IN} = 0V$	V <sub>CC</sub> = 3.6V or 0V		1.5   1.5	20   20	μA μA
$\Delta I_{IN}$	Change in Magnitude of I <sub>IN</sub>	$V_{IN} = V_{CC}$ $V_{IN} = 0V$	V <sub>IN</sub> = V <sub>CC</sub>		1	6	μΑ
V <sub>FSOD</sub>	Fail-safe BLVDS Outputs (OUT+ is a more positive	Inputs open, shorted, or	$R_L = 27\Omega$	250	350	500	mV
	voltage than OUT-) (Note 5)	terminated $R_L = 50\Omega$		350	450	600	mV
SUPPLY	CURRENT						
I <sub>CCD</sub>	Total Dynamic Supply Current (includes load current)	$EN = V_{CC}, R_{L} =$ $Freq. = 200MHz$ $V_{ID} = 200mV, V_{ID}$		50	65	mA	
I <sub>ccz</sub>	TRI-STATE Supply Current	$EN = 0V, Freq. = V_{ID} = 200 mV, V$	= 200MHz 50% duty cycle, C <sub>M</sub> = 1.2V		36	46	mA

## **AC Electrical Characteristics**

Over recommended operating supply and temperature ranges unless otherwise specified. (Note 3)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
LVDS OL	JTPUT AC SPECIFICATIONS (O	UT)				
t <sub>PHLD</sub>	Differential Propagation Delay High to Low (Note 10)	$V_{ID}$ = 200mV, $V_{CM}$ = 1.2V, $R_L$ = 27 $\Omega$ or 50 $\Omega$ , $C_L$ = 15pF Figure 3 and Figure 4	1.0	1.4	2.0	ns
t <sub>PLHD</sub>	Differential Propagation Delay Low to High (Note 10)		1.0	1.4	2.0	ns
t <sub>SKD1</sub>	Pulse Skew  t <sub>PLHD</sub> - t <sub>PHLD</sub>   (measure of duty cycle) (Notes 5, 6)		0	20	200	ps
t <sub>SKD3</sub>	Part-to-Part Skew (Note 5) (Note 7)		0	200	300	ps
t <sub>SKD4</sub>	Part-to-Part Skew (Note 5) (Note 8)		0		1	ns
t <sub>LHT</sub>	Rise Time (Notes 5, 10) 20% to 80% points	$R_L = 50\Omega$ or $27\Omega$ , $C_L = 15pF$ Figure 3 and Figure 5	0.350	0.6	1.0	ns

### AC Electrical Characteristics (Continued)

Over recommended operating supply and temperature ranges unless otherwise specified. (Note 3)

Symbol	Parameter	Parameter Conditions			Max	Units	
LVDS OUTPUT AC SPECIFICATIONS (OUT)							
t <sub>HLT</sub>	Fall Time (Notes 5, 10)		0.350	0.6	1.0	ns	
	80% to 20% points	D 500 0 45 5			0.5		
t <sub>PHZ</sub>	· ·	<del> </del>		3	25	ns	
t <sub>PLZ</sub>	Disable Time (Active Low to Z)	Figure 6 and Figure 7		3	25	ns	
$t_{PZH}$	Enable Time (Z to Active High)			100	120	ns	
t <sub>PZL</sub>	Enable Time (Z to Active Low)			100	120	ns	
t <sub>DJ</sub>	LVDS Data Jitter, Deterministic (Peak-to-Peak) (Note 9)	$V_{ID} = 300 \text{mV}$ ; PRBS = $2^{23} - 1 \text{ data}$ ; $V_{CM} = 1.2 \text{V at}$ 400Mbps (NRZ)			78	ps	
t <sub>RJ</sub>	LVDS Clock Jitter, Random (Note 9)	$V_{ID} = 300 \text{mV}$ ; $V_{CM} = 1.2 \text{V}$ at 200MHz clock			36	ps	
f <sub>MAX</sub>	Maximum guaranteed	V <sub>ID</sub> = 200mV, V <sub>CM</sub> = 1.2V		000			
	frequency (Note 11)		200	300		MHz	
LVCMOS	LUTTL AC SPECIFICATIONS (L	<u>-OS</u> )					
t <sub>PHLLOS</sub>	LVTTL Propagation Delay High to Low (Note 5)	$CL = 10pF, IN- = 1V, 1V \le IN+ \le 1.3V,$ Freq. = 10MHz, 50% Duty Cycle	10	15	20	ns	
t <sub>PLHLOS</sub>	LVTTL Propagation Delay Low to High (Note 5)	Figures 8, 9	2	5	10	ns	
t <sub>LHLOS</sub>	Rise Time 20% to 80% (Note 5)		1	2	3	ns	
t <sub>HLLOS</sub>	Fall Time 80% to 20% (Note 5)		1	1.3	3	ns	

**Note 1:** "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. They are not meant to imply that the device should be operated at these limits. The table of "Electrical Characteristics" specifies conditions of device operation.

**Note 2:** Current into device pins is defined as positive. Current out of device pins is defined as negative. All voltages are referenced to ground except  $V_{ID}$ ,  $V_{OD}$ ,  $V_{TH}$ ,  $V_{TL}$ , and  $\Delta V_{OD}$ .  $V_{OD}$  has a value and direction. Positive direction means OUT+ is a more positive voltage than OUT-.

- Note 3: All typical are given for  $V_{CC} = +3.3V$  and  $T_A = +25^{\circ}C$ , unless otherwise stated.
- Note 4: Output short circuit current (IOS) is specified as magnitude only, minus sign indicates direction only.
- Note 5: The parameters are guaranteed by design. The limits are based on statistical analysis of the device performance over the PVT (process, voltage and temperature) range.
- Note 6: t<sub>SKD1</sub>, It<sub>PLHD</sub> t<sub>PHLD</sub>I, is the magnitude difference in differential propagation delay time between the positive going edge and the negative going edge of the same channel (a measure of duty cycle).
- Note 7: t<sub>SKD3</sub>, Part to Part Skew, is defined as the difference between the minimum and maximum specified differential propagation delays. This specification applies to devices at the same V<sub>CC</sub> and within 5°C of each other within the operating temperature range. This parameter guaranteed by design and characterization.
- Note 8: t<sub>SKD4</sub>, Part to Part Skew, is the differential channel-to- channel skew of any event between devices. This specification applies to devices over recommended operating temperature and voltage ranges, and across process distribution. t<sub>SKD4</sub> is defined as IMax MinI differential propagation delay.
- Note 9: The parameters are guaranteed by design. The limits are based on statistical analysis of the device performance over the PVT range with the following test equipment setup: Agilent 86130A used as stimulus, 5 feet of RG142B cable with DUT test board and Agilent 86100A (digital scope mainframe) with Agilent 86122A (20GHz scope module). Data input jitter pk to pk = 22 picoseconds; Clock input jitter = 24 picoseconds; t<sub>DJ</sub> measured 100 picoseconds, t<sub>RJ</sub> measured 60 picoseconds
- Note 10: Propagation delay, rise and fall times are guaranteed by design and characterization to 200MHz. Generator for these tests:  $50MHz \le f \le 200MHz$ ,  $Zo = 50\Omega$ , tr, tf  $\le 0.5$ ns. Generator used was HP8130A (300MHz capability).
- Note 11: f<sub>MAX</sub> test: Generator (HP8133A or equivalent), Input duty cycle = 50%. Output criteria: VOD ≥ 200mV, Duty Cycle better than 45/55%. This specification is guaranteed by design and characterization. A minimum is specified, which means that the device will operate to specified conditions from DC to the minimum guaranteed AC frequency. The typical value is always greater than the minimum guarantee.

### **DC Test Circuits**

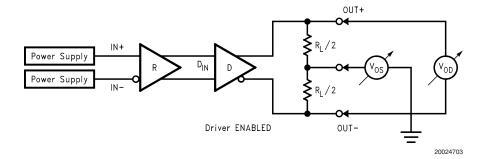


FIGURE 1. Differential Driver DC Test Circuit

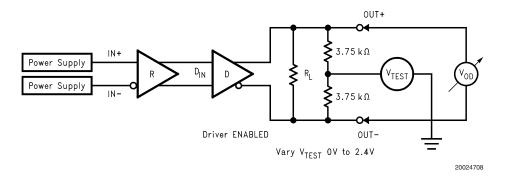


FIGURE 2. Differential Driver Full Load DC Test Circuit

# **AC Test Circuits and Timing Diagrams**

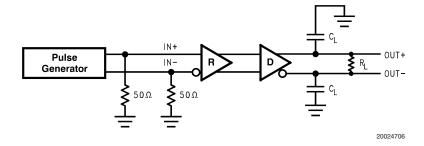


FIGURE 3. BLVDS Output Load

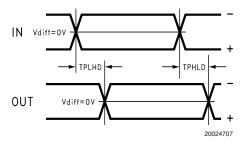


FIGURE 4. Propagation Delay Low-to-High and High-to-Low

# AC Test Circuits and Timing Diagrams (Continued)

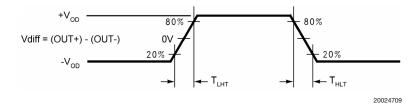


FIGURE 5. BLVDS Output Transition Time

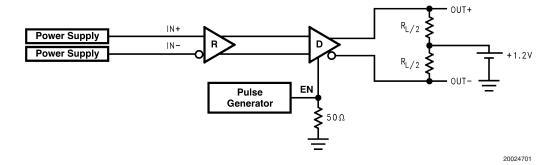


FIGURE 6. TRI-STATE Delay Test Circuit

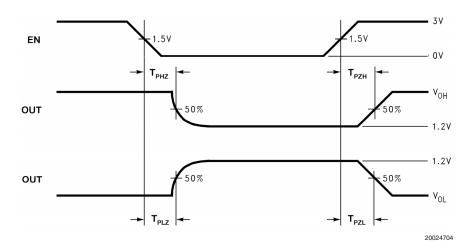


FIGURE 7. Output active to TRI-STATE and TRI-STATE to active output time

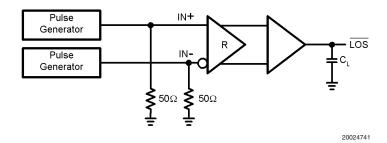


FIGURE 8. LOS Output Load for Propagation Delay, and Rise/Fall Times

# AC Test Circuits and Timing Diagrams (Continued)

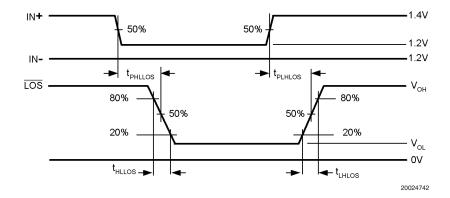


FIGURE 9. LOS Output Waveforms for Propagation Delay, and Rise/Fall Times

# DS92001 Pin Descriptions (SOIC and LLP)

Pin Name	Pin #	Input/Output	Description
GND	1	Р	Ground
IN –	2	I	Inverting receiver B/LVDS input pin
IN+	3	I	Non-inverting receiver B/LVDS input pin
LOS	4	0	Loss of Signal output pin.   TOS is asserted low while signal is invalid.
			See Applications Information section.
V <sub>CC</sub>	5	Р	Power Supply, 3.3V ± 0.3V.
OUT+	6	0	Non-inverting driver BLVDS output pin
OUT -	7	0	Inverting driver BLVDS output pin
EN	8	I	Enable pin. When EN is LOW, the driver is disabled and the BLVDS
			outputs are in TRI-STATE. When EN is HIGH, the driver is enabled.
			LVCMOS/LVTTL levels.
GND	DAP	Р	LLP Package Ground

# **Typical Applications**

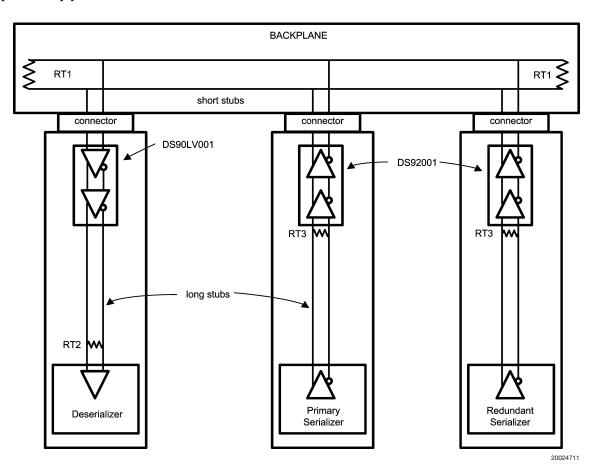


FIGURE 10. Backplane Stub-Hider Application

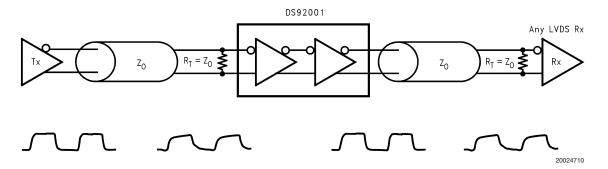


FIGURE 11. Cable Repeater Application

## **Application Information**

The DS92001 can be used as a "stub-hider." In many systems, signals are distributed across backplanes, and one of the limiting factors for system speed is the "stub length" or the distance between the transmission line and the unterminated receivers on the individual cards. See Figure 10. Although it is generally recognized that this distance should be as short as possible to maximize system performance, real-world packaging concerns and PCB designs often make it difficult to make the stubs as short as the designer would like. The DS92001, available in the LLP (Leadless Leadframe Package) package, can improve system performance by allowing the receiver to be placed very close to the main transmission line either on the backplane itself or very close to the connector on the card. Longer traces to the LVDS receiver may be placed after the DS92001. This very small LLP package is a 75% space savings over the SOIC pack-

The DS92001 may also be used as a repeater as shown in *Figure 11*. The signal is recovered and redriven at full strength down the following segment. The DS92001 may also be used as a level translator, as it accepts LVDS, BLVDS, and LVPECL inputs.

### **LOS DETECTION**

The  $\overline{LOS}$  pin presents a logic High level during normal operation (I100ImV  $\leq$  V<sub>ID</sub>  $\leq$  I2IV, of the device. When normal transmission stops the  $\overline{LOS}$  pin is asserted low. This occurs when the signal's source is removed, or turned-off (TRI-STATE). When the input signal voltage (V<sub>ID</sub>) is less than I10I millivolts the  $\overline{LOS}$  pin is asserted Low. For normal operation, Rise and Fall times presented to the B/LVDS inputs must be faster than 20 nanoseconds (20% to 80%) to avoid a loss of signal detection. Typical input transitions are in the 1-3 nanosecond range. In the case of a decaying signal (such as valid

signal to TRI-STATE), the slope should be monotonic to avoid glitches in the  $\overline{\text{LOS}}$  detection.

LOS Detection - Output Low

### POWER DECOUPLING RECOMMENDATIONS

Bypass capacitors must be used on power pins. Use high frequency ceramic (surface mount is recommended)  $0.1\mu F$  and  $0.01\mu F$  capacitors in parallel at the power supply pin with the smallest value capacitor closest to the device supply pin. Additional scattered capacitors over the printed circuit board will improve decoupling. Multiple vias should be used to connect the decoupling capacitors to the power planes. A  $10\mu F$  (35V) or greater solid tantalum capacitor should be connected at the power entry point on the printed circuit board between the supply and ground.

### PC BOARD CONSIDERATIONS

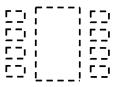
Use at least 4 PCB board layers (top to bottom): LVDS signals, ground, power, TTL signals.

Isolate TTL signals from LVDS signals, otherwise the TTL signals may couple onto the LVDS lines. It is best to put TTL and LVDS signals on different layers which are isolated by a power/ground plane(s).

Keep drivers and receivers as close to the (LVDS port side) connectors as possible.

For PC board considerations for the LLP package, please refer to application note AN-1187 "Leadless Leadframe Package." It is important to note that to optimize signal integrity (minimize jitter and noise coupling), the LLP thermal land pad, which is a metal (normally copper) rectangular region located under the package as seen in *Figure 12*, should be attached to ground and match the dimensions of the exposed pad on the PCB (1:1 ratio).

### **Top View**



20024744

FIGURE 12. LLP Thermal Land Pad and Pin Pads - Top View

### **DIFFERENTIAL TRACES**

Use controlled impedance traces which match the differential impedance of your transmission medium (ie. cable) and termination resistor. Run the differential pair trace lines as close together as possible as soon as they leave the IC (stubs should be < 10mm long). This will help eliminate reflections and ensure noise is coupled as common-mode. In fact, we have seen that differential signals which are 1mm apart radiate far less noise than traces 3mm apart since magnetic field cancellation is much better with the closer

traces. In addition, noise induced on the differential lines is much more likely to appear as common-mode which is rejected by the receiver.

Match electrical lengths between traces to reduce skew. Skew between the signals of a pair means a phase difference between signals which destroys the magnetic field cancellation benefits of differential signals and EMI will result. Do not rely solely on the auto-route function for differential traces. Carefully review dimensions to match differential impedance and provide isolation for the differential lines. Minimize the number of vias and other discontinuities on the line.

### **Application Information** (Continued)

Avoid 90° turns (these cause impedance discontinuities). Use arcs or 45° bevels.

Within a pair of traces, the distance between the two traces should be minimized to maintain common-mode rejection of the receivers. On the printed circuit board, this distance should remain constant to avoid discontinuities in differential impedance. Minor violations at connection points are allowable.

#### **TERMINATION**

Use a termination resistor which best matches the differential impedance or your transmission line. The resistor should be between  $90\Omega$  and  $130\Omega$  for point-to-point links. Multidrop (driver in the middle) or multipoint configurations are typically terminated at both ends. The termination value may be lower than  $100\Omega$  due to loading effects and in the  $50\Omega$  to  $100\Omega$  range. Remember that the current mode outputs need the termination resistor to generate the differential voltage.

Surface mount 1% - 2% resistors are the best. PCB stubs, component lead, and the distance from the termination to the receiver inputs should be minimized. The distance between the termination resistor and the receiver should be < 10mm (12mm MAX).

### PROBING LVDS TRANSMISSION LINES

Always use high impedance (>  $100k\Omega$ ), low capacitance (< 2 pF) scope probes with a wide bandwidth (1 GHz) scope. Improper probing will give deceiving results.

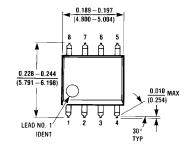
### **FAILSAFE FEATURE**

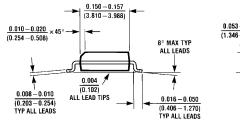
The BLVDS receiver is a high gain, high speed device that amplifies a small differential signal (30mV) to BLVDS ouput drive levels. Due to the high gain and tight threshold of the receiver, care should be taken to prevent noise from appearing as a valid signal.

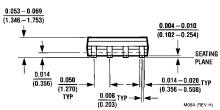
The receiver's internal fail-safe circuitry is designed to source/sink a small amount of current, providing fail-safe protection (a high level output voltage) for floating, terminated or shorted receiver inputs.

- 1. Terminated Input. If the driver is disconnected (cable unplugged), or if the driver is in a power-off condition, the BLVDS outputs will again be in a HIGH state, even with the end of cable 100Ω termination resistor across the input pins. The unplugged cable can become a floating antenna which can pick up noise. If the cable picks up more than 10mV of differential noise, the receiver may see the noise as a valid signal and switch. To insure that any noise is seen as common-mode and not differential, a balanced interconnect should be used. Twisted pair cable will offer better balance than flat ribbon cable.
- Shorted Inputs. If a fault condition occurs that shorts the receiver inputs together, thus resulting in a 0V differential input voltage, the BLVDS outputs will remain in a HIGH state. Shorted input fail-safe voltage range is 0V to 2.4V.
- 3. **External Biasing.** External lower value pull up and pull down resistors (for a stronger bias) may be used to boost fail-safe in the presence of higher noise levels. The pull up and pull down resistors should be in the  $5k\Omega$  to  $15k\Omega$  range to minimize loading and waveform distortion to the driver. The common-mode bias point should be set to approximately 1.2V (less than 1.75V) to be compatible with the internal circuitry. Please refer to application note AN-1194 "Failsafe Biasing of LVDS Interfaces" for more information.

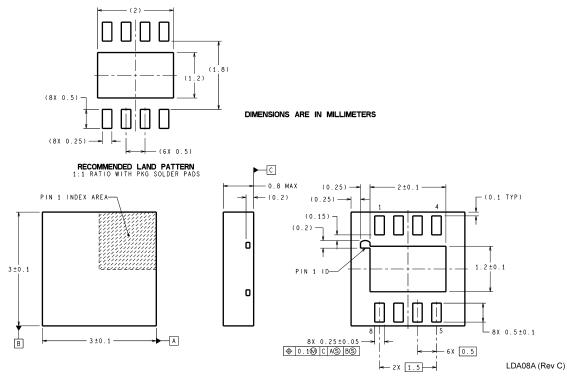








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Order Number DS92001TLD See NS Package Number LDA08A

### **Notes**

National does not assume any responsibility for use of any circuitry described, no circuit patent licenses are implied and National reserves the right at any time without notice to change said circuitry and specifications.

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